

AMENDMENTS TO THE SPECIFICATION

In the specification:

Please amend page 12, lines 1-13 to read as follows:

The apparatus of the present invention is shown in ~~Figure 6~~ Figure 11. An article, such as, but not limited to preform 3, is exposed to radiation 2 substantially in the near infrared region from radiation source 1. Suitable radiation sources include incandescent, quartz, halogen, arc lamps, metal oxide lamps, light emitting diodes, lasers and the like. For the purposes of this invention the near infrared region is extends from about 700 nm to about 2000 nm, and preferably from about 700 nm to about 1100nm. It should be understood that other wavelengths of light may also be emitted by the radiation source, so long as a substantial portion is within the near infrared. Use of a light source that produces light only in the near infrared can enhance the contrast of the image to allow easier visualization of the defects without the use of the aforementioned optical filter and may be preferred in certain embodiments.

In the Abstract:

Please amend the Abstract to read as follows:

~~The present invention relates to~~ An apparatus and method for detecting defects in colored articles includes ~~Specifically, the present invention comprises~~ exposing a plastic colored article to radiation in the near infrared range; measuring radiation returned from or passed through ~~said the~~ the article and analyzing ~~said the~~ the returned or passed radiation to provide defect data for ~~said the~~ the article or contents within ~~said the~~ the article.